Freescale Semiconductor

Technical Data

RF Power Field Effect Transistor Array

N-Channel Enhancement-Mode Lateral MOSFET

Designed for broadband commercial and industrial applications with frequencies to 1000 MHz. The high gain and broadband performance of this device make it ideal for large-signal, common-source amplifier applications in 26 volt base station equipment. The device is in a PFP-16 Power Flat Pack package which gives excellent thermal performances through a solderable backside contact.

• Typical Performance at 960 MHz, 26 Volts Output Power — 2 Watts Per Transistor Power Gain — 18 dB Efficiency — 50%

Capable of Handling 10:1 VSWR, @ 26 Vdc, 960 MHz, 2 Watts CW **Output Power**

Features

- · Designed for Maximum Gain and Insertion Phase Flatness
- · Excellent Thermal Stability
- Characterized with Series Equivalent Large-Signal Impedance Parameters
- **RoHS Compliant**
- In Tape and Reel. R2 Suffix = 1,500 Units per 16 mm, 13 inch Reel.

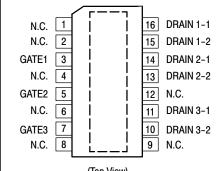
Rev. 8, 5/2006

Document Number: MRF9002NR2

MRF9002NR2

1000 MHz, 2 W, 26 V **LATERAL N-CHANNEL BROADBAND RF POWER MOSFET**





(Top View) Exposed backside flag is source Note: terminal for transistors.

Figure 1. Pin Connections

Table 1. Maximum Ratings

Rating		Value	Unit
Drain-Source Voltage	V _{DSS}	- 0.5, +65	Vdc
Gate-Source Voltage	V _{GS}	- 0.5, + 15	Vdc
Total Dissipation Per Transistor @ T _C = 25°C		4	W
Storage Temperature Range		- 65 to +150	°C
Operating Junction Temperature		150	°C

Table 2. Thermal Characteristics

Characteristic	Symbol	Value ⁽¹⁾	Unit
Thermal Resistance, Junction to Case, Single Transistor		12	°C/W

Table 3. Moisture Sensitivity Level

Test Methodology	Rating	Package Peak Temperature	Unit
Per JESD 22-A113, IPC/JEDEC J-STD-020	3	260	°C

^{1.} MTTF calculator available at http://www.freescale.com/rf. Select Tools/Software/Application Software/Calculators to access the MTTF calculators by product.

NOTE - CAUTION - MOS devices are susceptible to damage from electrostatic charge. Reasonable precautions in handling and packaging MOS devices should be observed.



Table 4. Electrical Characteristics ($T_C = 25$ °C unless otherwise noted)

Characteristic	Symbol	Min	Тур	Max	Unit
On Characteristics					
Gate Threshold Voltage $(V_{DS} = 10 \text{ Vdc}, I_D = 20 \mu\text{Adc})$	V _{GS(th)}	2.4	_	4	Vdc
Gate Quiescent Voltage (V _{DS} = 26 Vdc, I _D = 25 mAdc)	V _{GS(Q)}	3	_	5	Vdc
Drain-Source On-Voltage (V _{GS} = 10 Vdc, I _D = 0.1 Adc)	V _{DS(on)}	_	0.3	_	Vdc
Functional Tests (Per Transistor in Freescale Test Fixture, 5	50 ohm system)				
Common-Source Amplifier Power Gain @ P1dB (V _{DD} = 26 Vdc, I _{DQ} = 25 mA, f = 960.0 MHz)	G _{ps}	15	18		dB
Drain Efficiency @ P1dB (V _{DD} = 26 Vdc, I _{DQ} = 25 mA, f = 960.0 MHz)	η	35	50	_	%
Input Return Loss @ P1dB (V _{DD} = 26 Vdc, I _{DQ} = 25 mA, f = 960.0 MHz)	IRL	_	- 15	- 9	dB
Power Output, 1 dB Compression Point (V _{DD} = 26 Vdc, I _{DQ} = 25 mA, f = 960.0 MHz)	P _{1dB}	34	37	_	dBm

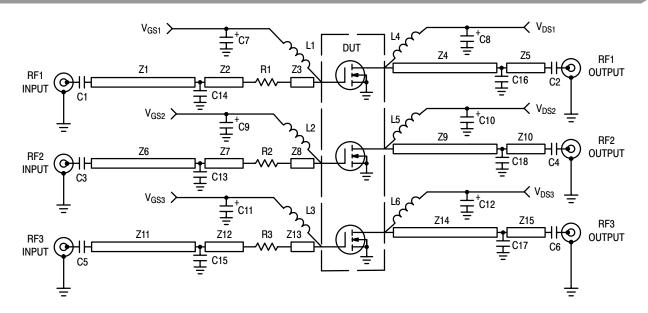
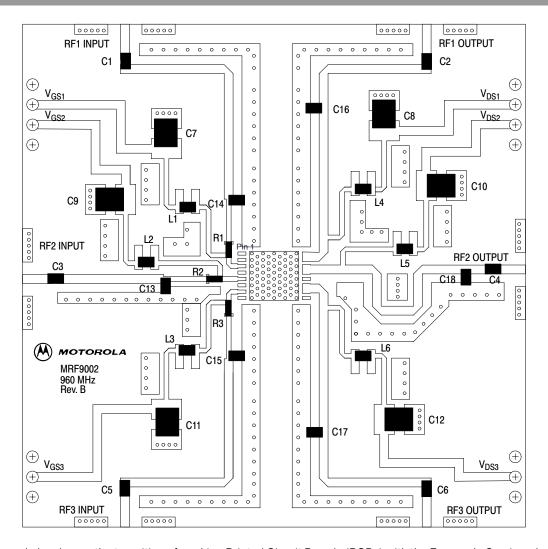


Figure 2. MRF9002NR2 Broadband Test Circuit Schematic

Table 5. MRF9002NR2 Broadband Test Circuit Component Designations and Values

Designators	Description	
C1-C6	33 pF Chip Capacitors (0805)	
C7-C12	1.0 μF, 35 V Tantalum Capacitors, B Case, Kemet	
C13	8.2 pF Chip Capacitor (0805)	
C14, C15	10 pF Chip Capacitors (0805)	
C16, C17	2.7 pF Chip Capacitors (0805)	
C18	3.3 pF Chip Capacitor (0805)	
L1-L6	12 nH Chip Inductors (0805)	
R1-R3	0 Ω Chip Resistors (0805)	
Z1, Z11	1.16 x 28.5 mm Microstrip	
Z2, Z7, Z12	0.65 x 5.6 mm Microstrip	
Z3, Z8, Z13	0.65 x 2.6 mm Microstrip	
Z4, Z14	1.16 x 19.5 mm Microstrip	
Z5, Z15	1.16 x 17.5 mm Microstrip	
Z6	1.16 x 12.9 mm Microstrip	
Z9	1.16 x 27.2 mm Microstrip	
Z10	1.16 x 4.3 mm Microstrip	
PCB	Etched Circuit Board	
Raw PCB Material	Rogers RO4350, 0.020", 2.5", x 2.5", ε _r = 3.5	
Bedstead	Copper Heatsink	



Freescale has begun the transition of marking Printed Circuit Boards (PCBs) with the Freescale Semiconductor signature/logo. PCBs may have either Motorola or Freescale markings during the transition period. These changes will have no impact on form, fit or function of the current product.

Figure 3. MRF9002NR2 Broadband Test Circuit Component Layout

TYPICAL CHARACTERISTICS

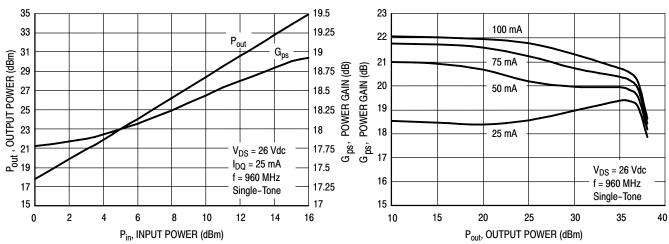


Figure 4. Output Power and Power Gain versus Input Power

Figure 5. Power Gain versus Output Power

Figure 7. Intermodulation Distortion versus

Output Power

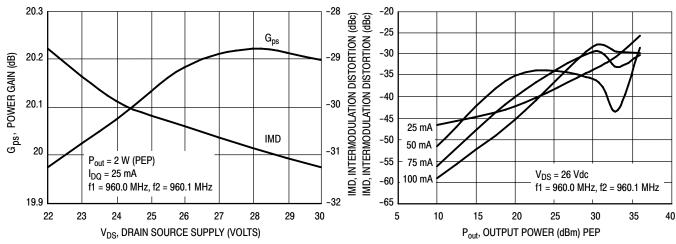


Figure 6. Power Gain and Intermodulation Distortion versus Supply Voltage

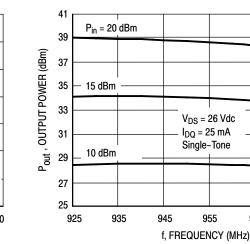


Figure 9. Output Power versus Frequency

965

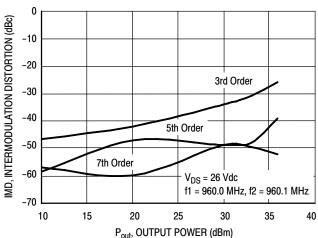


Figure 8. Intermodulation Distortion Products versus Output Power

MRF9002NR2

985

975

TYPICAL CHARACTERISTICS

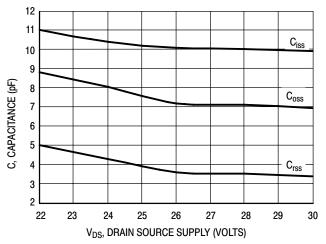
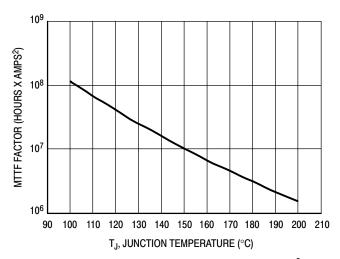
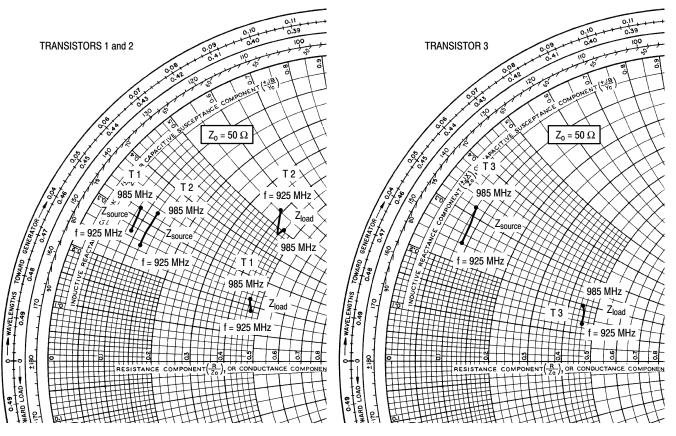


Figure 10. Capacitance versus Drain Source Voltage



This above graph displays calculated MTTF in hours x ampere² drain current. Life tests at elevated temperatures have correlated to better than $\pm 10\%$ of the theoretical prediction for metal failure. Divide MTTF factor by $I_D{}^2$ for MTTF in a particular application.

Figure 11. MTTF Factor versus Junction Temperature



 V_{DD} = 26 V, I_{DQ} = 25 mA, P_{out} = 2 W PEP

f MHz	$\mathbf{Z_{source}}_{\Omega}$	Z_{load} Ω
925	4.5 + j13.3	23.4 + j9.2
960	4.3 + j15.3	23.2 + j10.4
985	4.1 + j15.8	23.0 + j11.1

Transistor 1

 V_{DD} = 26 V, I_{DQ} = 25 mA, P_{out} = 2 W PEP

f MHz	$\mathbf{Z_{source}}_{\Omega}$	$\mathbf{Z_{load}}_{\Omega}$
925	6.0 + j12.3	19.7 + j27.8
960	5.9 + j14.3	22.0 + j23.9
985	5.8 + j16.5	22.5 + j25.4

Transistor 2

 V_{DD} = 26 V, I_{DQ} = 25 mA, P_{out} = 2 W PEP

DD - 7 DQ - 7 OUL			
f MHz	$\mathbf{Z_{source}}_{\Omega}$	$oldsymbol{Z_{load}}{\Omega}$	
925	4.3 + j12.2	23.1 + j6.5	
960	4.3 + j14.0	22.8 + j8.4	
985	3.9 + j15.9	22.6 + j9.3	

Transistor 3

Z_{source} = Test circuit impedance as measured from gate to ground.

Z_{load} = Test circuit impedance as measured from drain to ground.

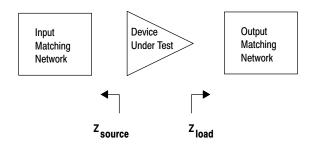


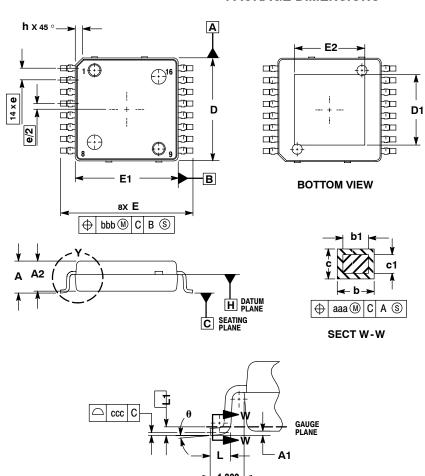
Figure 12. Series Equivalent Source and Load Impedance

NOTES

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NOTES

PACKAGE DIMENSIONS



DETAIL Y

CASE 978-03 ISSUE C PLASTIC

PFP-16

NOTES:

- 1. CONTROLLING DIMENSION: MILLIMETER.
 2. DIMENSIONS AND TOLERANCES PER ASME

- 2. DIMENSIONS AND TOLERANCES PER ASME
 Y14.5M, 1994.
 3. DATUM PLANE -H- IS LOCATED AT BOTTOM OF
 LEAD AND IS COINCIDENT WITH THE LEAD
 WHERE THE LEAD EXITS THE PLASTIC BODY AT
 THE BOTTOM OF THE PARTING LINE.
 4. DIMENSIONS D AND E1 DO NOT INCLUDE MOLD
 PROTRUSION. ALLOWABLE PROTRUSION IS
 0.250 PER SIDE. DIMENSIONS D AND E1 DO
 INCLUDE MOLD MISMATCH AND ARE
 DETERMINED AT DATUM PLANE -H-.
 5. DIMENSION b DOES NOT INCLUDE DAMBAR
 PROTRUSION. ALLOWABLE DAMBAR
 PROTRUSION. ALLOWABLE DAMBAR
 PROTRUSION ALLOWABLE DAMBAR
 PROTRUSION AT MAXIMUM MATERIAL
 CONDITION.
 6. DATUMS -A- AND -B- TO BE DETERMINED AT
- 6. DATUMS -A- AND -B- TO BE DETERMINED AT DATUM PLANE -H-.

	MILLIMETERS		
DIM	MIN	MAX	
Α	2.000	2.300	
A1	0.025	0.100	
A2	1.950	2.100	
D	6.950	7.100	
D1	4.372	5.180	
Е	8.850	9.150	
E1	6.950	7.100	
E2	4.372	5.180	
L	0.466	0.720	
L1	0.250 BSC		
b	0.300	0.432	
b1	0.300	0.375	
C	0.180	0.279	
c1	0.180	0.230	
е	0.800 BSC		
h		0.600	
θ	0°	7°	
aaa	0.200		
bbb	0.200		
CCC	0.100		

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